Contents

PREFACE (A. J. C. Wilson)	XXIX
PART 1: CRYSTAL GEOMETRY AND SYMMETRY	1
1.1. SUMMARY OF GENERAL FORMULAE (E. Koch)	2
1.1.1. General relations between direct and reciprocal lattices	2
1.1.1.1. Primitive crystallographic bases 1.1.1.2. Non-primitive crystallographic bases	2 2
Table 1.1.1.1. Direct and reciprocal lattices described with respect to conventional basis systems	3
1.1.2. Lattice vectors, point rows, and net planes	3
1.1.3. Angles in direct and reciprocal space	4
1.1.4. The Miller formulae	4

1.2.	APPLI	CATION TO THE CRYSTAL SYSTEMS (E. Koch)	6
	1.2.1.	Triclinic crystal system	6
	1.2.2.	Monoclinic crystal system	6
		1.2.2.1. Setting with 'unique axis b' 1.2.2.2. Setting with 'unique axis c'	6 6
	1.2.3.	Orthorhombic crystal system	6
	1.2.4.	Tetragonal crystal system	7
		Table 1.2.4.1. Assignment of integers $s \le 100$ to pairs h, k with $s = h^2 + k^2$	7
	1.2.5.	Trigonal and hexagonal crystal system	7
		1.2.5.1. Description referred to hexagonal axes 1.2.5.2. Description referred to rhombohedral axes	7 8
		Table 1.2.5.1. Assignment of integers $s \le 100$ to pairs h, k with $s = h^2 + k^2 + hk$ Table 1.2.5.2. Assignment of integers $s_1 \le 50$ to triplets h, k, l with $s_1 = h^2 + k^2 + l^2$ and to integers	7
		$s_2 = hk + hl + kl$	8
	1.2.6.	Cubic crystal system	9
		Table 1.2.6.1. Assignment of integers $s \le 100$ to triplets h, k, l with $s = h^2 + k^2 + l^2$	9

1.3. TWINNING (E. Koch)

131 Conoral remarks

10

	1.3.1.	General remarks	10
	1.3.2.	Twin lattices	10
		Table 1.3.2.1. Lattice planes and rows that are perpendicular to each other independently of the metrical parameters	11
	1.3.3.	Implication of twinning in reciprocal space	12
	1.3.4.	Twinning by merohedry	12
		Table 1.3.4.1. Possible twin operations for twins by merohedry Table 1.3.4.2. Simulated Laue classes, extinction symbols, simulated 'possible space groups', and possible	13
	135	Calculation of the twin element	13
	1.0.01		
1.4.	ARITH	METIC CRYSTAL CLASSES (A. J. C. Wilson)	15
		Table 1.4.1. The two-dimensional arithmetic crystal classesTable 1.4.2. The three-dimensional space groups arranged by arithmetic crystal classTable 1.4.3. Arithmetic crystal classes classified by the number of space groups that they contain	15 16 20
	Refere	nces	20

PA	RT 2:	DIFFRACTION GEOMETRY AND ITS PRACTICAL REALIZATION	23
2.1.	CLASS	IFICATION OF EXPERIMENTAL TECHNIQUES (J. R. Helliwell)	24
	Table	2.1.1. Summary of main experimental techniques for structure analysis	25
2.2.	Singl	e-Crystal X-ray Techniques (J. R. Helliwell)	26
	2.2.1.	Laue geometry	26
		 2.2.1.1. General 2.2.1.2. Crystal setting 2.2.1.3. Single-order and multiple-order reflections 2.2.1.4. Nodal reflections 2.2.1.5. Gnomonic and stereographic transformations 	26 27 27 29 29
	2.2.2.	Monochromatic still exposure	29
		2.2.2.1. General 2.2.2.2. Crystal setting	29 29
	2.2.3.	Rotation/oscillation geometry	29
		 2.2.3.1. General 2.2.3.2. Diffraction coordinates 2.2.3.3. Relationship of reciprocal-lattice coordinates to crystal system parameters 2.2.3.4. Maximum oscillation angle without spot overlap 2.2.3.5. Blind region 	29 30 32 33 33
		Table 2.2.3.1. Glossary of symbols used to specify quantities on diffraction patterns and in reciprocal space	31
	2.2.4.	Weissenberg geometry	33
		 2.2.4.1. General 2.2.4.2. Recording of zero layer 2.2.4.3. Recording of upper layers 	33 33 34
	2.2.5.	Precession geometry	34
		 2.2.5.1. General 2.2.5.2. Crystal setting 2.2.5.3. Recording of zero-layer photograph 2.2.5.4. Recording of upper-layer photographs 2.2.5.5. Recording of cone-axis photograph 	34 34 35 35
		Table 2.2.5.1. The distance displacement measured on the film versus angular setting error of the crystal for a screenless precession ($\mu = 5^{\circ}$) setting photograph	34
	2.2.6.	Diffractometry	35
		2.2.6.1. General 2.2.6.2. Normal-beam equatorial geometry	35 35
		2.2.6.3. Fixed $\chi = 45^{\circ}$ geometry with area detector	36
	2.2.7.	Practical realization of diffraction geometry: sources, optics, and detectors	36
		2.2.7.1. General 2.2.7.2. Conventional X-ray sources: spectral character, crystal rocking curve, and spot size 2.2.7.3. Synchrotron X-ray sources	36 36 38
		2.2.7.4. Geometric effects and distortions associated with area detectors	40
2.3	. Powr	der and Related Techniques: X-ray Techniques (W. Parrish)	42
	2.3.1.	Focusing diffractometer geometries	43
		2.3.1.1. Conventional reflection specimen, θ -2 θ scan	44
		 2.3.1.1.1. Geometrical instrument parameters 2.3.1.1.2. Use of monochromators 2.3.1.1.3. Alignment and angular calibration 2.3.1.1.4. Instrument broadening and aberrations 2.3.1.1.5. Focal line and receiving-slit widths 2.3.1.1.6. Aberrations related to the specimen 2.3.1.1.7. Axial divergence 2.3.1.1.8. Combined aberrations 	44 46 46 47 48 48 50 50
		2.3.1.2. Transmission specimen, θ -2 θ scan	50

		2.3.1.3. Seemann-Bohlin method 2.3.1.4. Reflection specimen, $\theta - \theta$ scan 2.3.1.5. Microdiffractometry	52 53
	2.3.2.	Parallel-beam geometries, synchrotron radiation	55
		2.3.2.1. Monochromatic radiation, $\theta - 2\theta$ scan 2.3.2.2. Cylindrical specimen, 2θ scan 2.3.2.3. Grazing-incidence diffraction 2.3.2.4. High-resolution energy-dispersive diffraction	55 57 57 58
	2.3.3.	Specimen factors, angle, intensity, and profile-shape measurement	59
		2.3.3.1. Specimen factors	60
		2.3.3.1.1. Preferred orientation 2.3.3.1.2. Crystallite-size effects	60 61
		 2.3.3.2. Problems arising from the Kα doublet 2.3.3.3. Use of peak or centroid for angle definition 2.3.3.4. Rate-meter/strip-chart recording 2.3.3.5. Computer-controlled automation 2.3.3.6. Counting statistics 2.3.3.7. Peak search 2.3.3.8. Profile fitting 2.3.3.9. Computer graphics for powder patterns Table 2.3.3.1. Preferred-orientation data for silicon 	62 63 63 64 65 65 68 61
		Table 2.3.3.2. R (Bragg) values obtained with different preferred-orientation formulae	61
	2.3.4.	Powder cameras	69 70
		 2.3.4.1. Cylindrical cameras (Debye-Scherrer) 2.3.4.2. Focusing cameras (Guinier) 2.3.4.3. Miscellaneous camera types 	70 70 70
	2.3.5.	Generation, modifications, and measurement of X-ray spectra	71
		2.3.5.1. X-ray tubes	71
		 2.3.5.1.1. Stability 2.3.5.1.2. Spectral purity 2.3.5.1.3. Source intensity distribution and size 2.3.5.1.4. Air and window transmission 2.3.5.1.5. Intensity variation with take-off angle 	72 72 72 73 73
		2.3.5.2. X-ray spectra	74
		2.3.5.2.1. Wavelength selection	75
		2.3.5.3. Other X-ray sources 2.3.5.4. Methods for modifying the spectrum	75 75
		2.3.5.4.1. Crystal monochromators 2.3.5.4.2. Single and balanced filters	75 77
		Table 2.3.5.1. X-ray tube maximum ratings Table 2.3.5.2. β filters for common target elements Table 2.3.5.3. Calculated thickness of balanced filters for common target elements	71 78 79
2.4.	Powd	er and Related Techniques: Electron and Neutron Techniques	80
	2.4.1.	Electron techniques (J. M. Cowley)	80
		 2.4.1.1. Powder-pattern geometry 2.4.1.2. Diffraction patterns in electron microscopes 2.4.1.3. Preferred orientations 2.4.1.4. Powder-pattern intensities 2.4.1.5. Crystal-size analysis 2.4.1.6. Unknown-phase identification: databases 	80 80 80 80 81 81
	2.4.2.	Neutron techniques (A. W. Hewat)	82
2.5.	Ener	gy-Dispersive Techniques	84
	2.5.1.	Techniques for X-rays (B. Buras and L. Gerward)	84
		2.5.1.1. Recording powder-diffraction spectra	84

		 2.5.1.2. Incident X-ray beam 2.5.1.3. Resolution 2.5.1.4. Integrated intensity for powder sample 2.5.1.5. Corrections 2.5.1.6. The Rietveld method 2.5.1.7. Applications 2.5.1.8. Single-crystal diffraction 	84 85 85 86 86 87 87
	2.5.2.	White-beam and time-of-flight neutron diffraction (J. D. Jorgensen, W. I. F. David, and B. T. M. Willis)	87
		2.5.2.1. Neutron single-crystal Laue diffraction 2.5.2.2. Neutron time-of-flight powder diffraction	87 88
2.6.	Smali	-Angle Techniques	89
	2.6.1.	X-ray techniques (O. Glatter)	89
		 2.6.1.1. Introduction 2.6.1.2. General principles 2.6.1.3. Monodisperse systems 	89 90 91
		2.6.1.3.1. Parameters of a particle 2.6.1.3.2. Shape and structure of particles 2.6.1.3.3. Interparticle interference, concentration effects	91 93 97
		2.6.1.4. Polydisperse systems 2.6.1.5. Instrumentation	99 99
		2.6.1.5.1. Small-angle cameras 2.6.1.5.2. Detectors	99 1′00
		2.6.1.6. Data evaluation and interpretation	100
		 2.6.1.6.1. Primary data handling 2.6.1.6.2. Instrumental broadening - smearing 2.6.1.6.3. Smoothing, desmearing, and Fourier transformation 2.6.1.6.4. Direct structure analysis 2.6.1.6.5. Interpretation of results 	101 101 101 103 103
		2.6.1.7. Simulations and model calculations	103
		Table 2.6.1.1. Formulae for the various parameters for h and m scales	92
	2.6.2.	Neutron techniques (R. May)	105
		 2.6.2.1. Relation of X-ray and neutron small-angle scattering 2.6.2.2. Isotopic composition of the sample 2.6.2.3. Magnetic properties of the neutron 2.6.2.4. Long wavelengths 2.6.2.5. Sample environment 2.6.2.6. Incoherent scattering 2.6.2.7. Single-particle scattering 2.6.2.8. Dense systems 	105 107 108 108 108 108 110 112

2.7.	Торос	GRAPHY (A. R. Lang)	113
	2.7.1.	Principles	113
	2.7.2.	Single-crystal techniques	114
		2.7.2.1. Reflection topographs 2.7.2.2. Transmission topographs	114 115
	2.7.3.	Double-crystal topography	117
	2.7.4.	Developments with synchrotron radiation	119
		2.7.4.1. White-radiation topography 2.7.4.2. Incident-beam monochromatization	119 120
		Table 2.7.4.1. Monolithic monochromator for plane-wave synchrotron-radiation topography	121
	2.7.5.	Some special techniques	121
		2.7.5.1. Moiré topography 2.7.5.2. Real-time viewing of topograph images	121 122
	Refer	ences	123

PAI	RT 3: PREPARATION AND EXAMINATION OF SPECIMENS	137
3.1.	INVESTIGATION AND SELECTION OF CRYSTALS (C. H. MacGillavry and N. F. M. Henry)	138
	3.1.1. Selection of the specimen	138
	3.1.2. Preparation of the specimen	138
	3.1.3. Orientation of the specimen	138
	31.4. Preliminary information about the structure	138
	Table 2.1.1. Use of existal properties for selection and preliminary study of crystals	130
	Table 5.1.1. Use of crystal properties for selection and preliminary stady of crystals	139
3.2.	DETERMINATION OF THE DENSITY OF SOLIDS (F. M. Richards)	141
	3.2.1. Introduction	141
	3.2.1.1. General precautions	141
	3.2.2. Description and discussion of techniques	141
	3.2.2.1. Gradient tube	141
	3.2.2.2. Flotation method	142
	3.2.2.3. Pycnometry 3.2.2.4. Method of Archimedes	142
	3.2.2.5. Immersion microbalance	143
	3.2.2.6. Volumenometry	143
	3.2.2.7. Other procedures	143
	Table 3.2.2.1. Possible substances for use as gradient-column components	142
3.3.	MEASUREMENT OF REFRACTIVE INDEX (E. S. Larsen Jr and R. Meyrowitz)	144
	3.3.1. Media for general use	144
	Table 3.3.1.1. Immersion media for general use in the measurement of index of refraction	144
	3.3.2. High-index media	144
	3.3.3. Media for organic substances	144
	Table 3.3.3.1. Aqueous solutions for use as immersion media for organic crystals Table 3.3.3.2. Organic immersion media for use with organic crystals of low solubility	144 144
3.4.	MOUNTING AND SETTING OF SPECIMENS FOR X-RAY CRYSTALLOGRAPHIC STUDIES (P. F. Lindley)	145
	3.4.1. Mounting of specimens	145
	3.4.1.1 Introduction	145
	3.4.1.2. Polycrystalline specimens	145
	3.4.1.3. Single crystals	146
	3.4.1.4. Single crystals of biological macromolecules	147
	Table 3.4.1.1. Single-crystal and powder mounting – capillary tubes and other containers Table 3.4.1.2. Single crystal mounting adhesives	145
	a de Cattine of single crystal mounting - aunestoes	147
	3.4.2. Setting of single crystals by X-rays	147
	3.4.2.1. Introduction	147
	3.4.2.2. Fremmary considerations 3.4.2.3. Rotation-geometry setting with moving-crystal methods	148
	3.4.2.4. Precession-geometry setting with moving-crystal methods	148
	3.4.2.5. Setting with stationary-crystal methods	148
	3.4.2.6. Rotation-geometry setting for crystals with large unit cens 3.4.2.7. Diffractometer-setting considerations	149
3.5.	PREPARATION OF SPECIMENS FOR ELECTRON DIFFRACTION AND ELECTRON MICROSCOPY (N. J. Tighe,	150
	J. R. Fryer, and H. M. Flower)	150
	3.5.1. Ceramics and rock minerals	150
	3.5.1.1. Thin tragments, particles, and makes	150
	3.5.1.2. Final thinning by argon-ion etching	151
	3.5.1.4. Final thinning by chemical etching	151
	3.5.1.5. Evaporated and sputtered thin films	152
	Table 3.5.1.1. Chemicals etchants used for preparing thin foils from single-crystal ceramic materials	152

3.5.2. Metals	152
3.5.2.1. Thin sections	152
3.5.2.2. Final thinning methods	153
3.5.2.3. Chemical and electrochemical thinning solutions	155
3.5.3. Polymers and organic specimens	154
3.5.3.1. Cast films	155
3.5.3.2. Sublimed films	155
J.J.J.J. Onenced sonaneactor	
3.6. Specimens for Neutron Diffraction (B. T. M. Willis)	156
References	156
PART 4: PRODUCTION AND PROPERTIES OF RADIATIONS	161
4.1. RADIATIONS USED IN CRYSTALLOGRAPHY (V. Valvoda)	162
411 Introduction	162
A 1.2 Floctromagnetic waves and narticles	162
4.1.2. Most froquently used radiations	163
4.1.5. MOSt frequently used faulations	163
Table 4.1.3.1. Average aigraction properties of X-rays, electrons, and neutrons	105
4.1.4. Special applications of X-rays, electrons, and neutrons	104
4.1.5. Other radiations	165
4.2. X-rays	167
4.2.1. Generation of X-ravs (U. W. Arndt)	167
4.2.1.1. The characteristic line spectrum	167
4.2.1.1.1. X-ray wavelengths: precision units and conversion factors	167
4.2.1.1.2. The intensity of characteristic lines	168
4.2.1.2. The continuous spectrum	169
4.2.1.3. X-ray tubes	170
4.2.1.3.1. Power dissipation in the anode	171
4.2.1.4. Radioactive X-ray sources	172
4.2.1.5. Synchrotron-radiation sources	172
4.2.1.6. Plasma X-ray sources	167
Table 4.2.1.1. Correspondence between X-ray diagram levels and electron configurations Table 4.2.1.2. Correspondence between IUPAC and Siegbahn notations for X-ray diagram lines	167
Table 4.2.1.3. Wavelength standards and conversion factors	168
Table 4.2.1.4. Copper-target X-ray tubes and their loading	171
Table 4.2.1.5. Relative permissible loading for different target materials	172
Table 4.2.1.6. Radionuclides decaying wholly by electron capture, and yielding little or no γ -radiation	172
Table 4.2.1.7. Comparison of storage-ring synchrotron-radiation sources Table 4.2.1.8. Intensity agin with storage rings over conventional sources	175
1010 4.2.1.0. Intensity gain with storage rings over conventional sources	176
4.2.2. A-ray wavelengths (U. W. Arnut) T-11- (2.2.1. Wewelengths of K emission series and cheamtion adapts	177
Table 4.2.2.1. Wavelengths of K-emission series and absorption edges Table 4.2.2.2. Wavelengths of L-emission series and absorption edges	180
473 X-ray absorption spectra (D. C. Creagh)	182
4231 Introduction	182
4.2.3.1. Introduction A 2 2 1 1 Definitions	182
4.2.3.1.2. Variation of X-ray attenuation coefficients with photon energy	183
4.2.3.1.3. Normal attenuation, EXAFS, and XANES	183
4.2.3.2. Techniques for the measurement of X-ray attenuation coefficients	184
4.2.3.2.1. Experimental configurations	184
4.2.3.2.2. Specimen selection	184
4.2.3.2.3. Requirements for the absolute measurement of μ_l or (μ/ρ)	192

	4.2.3.3. 4.2.3.4.	Normal attenuation coefficients Attenuation coefficients in the neighbourhood of an absorption edge	185 185
		4.2.3.4.1. EXAFS	185
		4.2.3.4.1.1. Theory	185
		4.2.3.4.1.2. Techniques of data analysis	186
		4.2.3.4.1.3. EXAFS experiments	187
		4.2.3.4.2. X-ray absorption near edge structure (XANES)	188
	4.2.3.5.	Comments	188
	Table 4	4.2.3.1. Some synchrotron-radiation facilities providing EXAFS data bases and analysis utilities	189
4.2.4.	X-ray al	bsorption (or attenuation) coefficients (D. C. Creagh and J. H. Hubbell)	189
	4.2.4.1. 4.2.4.2.	Introduction Sources of information	189 190
		4.2.4.2.1. Theoretical photo-effect data: σ_{pe}	190
		4.2.4.2.2. Theoretical Rayleigh scattering data: σ_R	190
	1212	$-4.2.4.2.5$. Theoretical compton scattering data. σ_C	191
	4.2.4.3.	Uncertainty in the data tables	191 192
	Table 4	2.2.4.1. Table of wavelengths and energies for the characteristic radiations used in the subsequent tables	192
	Table 4	2.4.3. Mass attenuation coefficients	200
4.2.5.	Filters a	and monochromators (A. J. C. Wilson)	206
4.2.6.	X-ray di	ispersion corrections (D. C. Creagh and W. J. McAuley)	206
	4.2.6.1.	Definitions	207
		4.2.6.1.1. Rayleigh scattering	207
		4.2.6.1.2. Thomson scattering by a free electron 4.2.6.1.3. Elastic scattering from electrons bound to atoms: the atomic scattering factor, the atomic	207
		form factor, and the dispersion corrections	207
	4.2.6.2.	Theoretical approaches for the calculation of the dispersion corrections	208
		4.2.6.2.1. The classical approach	208
		4.2.6.2.3. Relativistic theories	209
		4.2.6.2.3.1. Cromer and Liberman: relativistic dipole approach 4.2.6.2.3.2. The scattering matrix formalism	209 211
		4.2.6.2.4. Intercomparison of theories	212
	4.2.6.3.	Modern experimental techniques	214
		4.2.6.3.1. Determination of the real part of the dispersion correction: $f'(\omega, 0)$ 4.2.6.3.2. Determination of the real part of the dispersion correction: $f'(\omega, \Delta)$	214 215
		4.2.6.3.2.1. Measurements using the dynamical theory of X-ray diffraction 4.2.6.3.2.2. Friedel- and Bijvoet-pair techniques	215 215
		4.2.6.3.3. Comparison of theory with experiment	216
		4.2.6.3.3.1. Measurements in the high-energy limit $(\omega/\omega_{\kappa} \rightarrow 0)$	216
		4.2.6.3.3.2. Measurements in the vicinity of an absorption edge	217
		4.2.6.3.3.3. Accuracy in the tables of dispersion corrections 4.2.6.3.3.4. Summary	218 218
	4.2.6.4.	Table of wavelengths, energies, and linewidths used in compiling the tables of the dispersion corrections	219
	4.2.6.5.	Tables of the dispersion corrections for forward scattering, averaged polarization using the relativistic multipole approach	219
	Table 4 Table 4	2.2.6.1. Values of E _{tot} /mc ² listed as a function of atomic number Z 2.2.6.2(a). Comparison between the S-matrix calculations of Kissel (1977) and the form-factor calculations of Cromer & Liberman (1970, 1981, 1983) and Creagh & McAuley for the	210
		noble gases and several common metals	213
	Table 4	(2.0.2(0). A comparison of the real part of the forward scattering amplitudes computed using different theoretical approaches	213

		 Table 4.2.6.3. A comparison of the imaginary part of the forward scattering amplitudes f"(ω, 0) computed using different theoretical approaches Table 4.2.6.4. Comparison of measurements of the real part of the dispersion correction for LiF, Al, Si, and Ge for characteristic wavelengths Ag Kα₁, Mo Kα₁ and Cu Kα₁ with theoretical predictions Table 4.2.6.5. Comparison of measurements of f"(ω, 0) for C, Si and Cu for characteristic wavelengths Ag Kα₁, Mo Kα₁ with theoretical predictions Table 4.2.6.6. Comparison of f'(ω_A, 0) for copper, nickel, zirconium, and niobium for theoretical and experimental data sets Table 4.2.6.7. List of wavelengths, energies, and linewidths used in compiling the table of dispersion corrections for forward scattering 	213 216 217 218 219 219
43	FLECT	TRON DIFFRACTION	223
	4.3.1.	Scattering factors for the diffraction of electrons by crystalline solids (J. M. Cowley)	223
		4.3.1.1. Elastic scattering from a perfect crystal	223
		4.3.1.2. Atomic scattering factors	223 224
		4.3.1.4. Relativistic effects	224
		4.3.1.5. Absorption effects	225
		4.3.1.6. Tables of atomic scattering amplitudes for electrons 4.3.1.7. Use of the tables	225
		Table 4.3.1.1. Atomic scattering amplitudes for electrons for neutral atoms	226
		Table 4.3.1.2. Atomic scattering amplitudes for electrons for ionized atoms	235
	4.3.2.	Relativistic parameters as a function of accelerating voltage	245
		Table 4.3.2.1. Parameters useful in electron diffraction as a function of accelerating voltage, E	244
	4.3.3.	Complex scattering factors for the diffraction of electrons by gases (A. W. Ross, M. Fink, R. Hilderbrandt, J. Wang, and V. H. Smith Jr)	245
		4.3.3.1. Introduction	245
		4.3.3.2. Complex atomic scattering factors for electrons	245
		4.3.3.2.1. Elastic scattering factors for atoms 4.3.3.2.2. Total inelastic scattering factors	245
		4.3.3.2.3. Corrections for defects in the theory of atomic scattering	337
		4.3.3.3. Molecular scattering factors for electrons	337
		Table 4.3.3.1. Partial wave elastic scattering factors for neutral atoms Table 4.3.3.2. Inelastic scattering factors	247 327
	4.3.4.	Electron energy-loss spectroscopy on solids (C. Colliex)	338
		4.3.4.1. Definitions	338
		4.3.4.1.1. Use of electron beams 4.3.4.1.2. Parameters involved in the description of a single inelastic scattering event	338
		4.3.4.1.3. Problems associated with multiple scattering	339
		4.3.4.1.4. Classification of the different types of excitations contained in an electron energy-loss	340
		4342 Instrumentation	341
		43421 General instrumental considerations	341
		4.3.4.2.2. Spectrometers	341
		4.3.4.2.3. Detection systems	343
		4.3.4.3. Excitation spectrum of valence electrons	344
		4.3.4.3.1. Volume plasmons 4.3.4.3.2. Dielectric description	344 346
		4.3.4.3.3. Real solids	348
		4.3.4.3.4. Surface plasmons	350
		4.3.4.4. Excitation spectrum of core electrons	351
		4.3.4.4.1. Definition and classification of core edges 4.3.4.4.2. Bethe theory for inelastic scattering by an isolated atom	351 353
		4.3.4.4.3. Solid-state effects	355
		4.3.4.4.4. Applications of core-loss spectroscopy	351
		4.3.4.3. Conclusion	328

		Table 4.3.4.1. Different possibilities for using EELS information as a function of the different parameters $(\mathbf{r}, \theta, \Delta E)$	341
		Table 4.3.4.2. Plasmon energies measured (and calculated) for a few simple metals $\dots \dots \dots$ Table 4.3.4.3. Experimental and theoretical values for the coefficient α in the plasmon dispersion curve together with estimates of the cut off wavevector	344
		Table 4.3.4.4. Comparison of measured and calculated values for the halfwidth $\Delta E_{1/2}(0)$ of the plasmon line	345 345
	4.3.5.	Oriented texture patterns (B. B. Zvyagin)	359
		4.3.5.1. Texture patterns	359
		4.3.5.2. Lattice plane oriented perpendicular to a direction (lamellar texture)	359
		4.3.5.3. Lattice direction oriented parallel to a direction (fibre texture)	360
	A 2 6	Computation of dynamical wave amplitudes	360
	4.3.0.	-4.2.6.1 The multiplice method (D) E. Lunch)	200
		4.3.6.2. The Bloch wave method (A. Howie)	362
	4.3.7.	Measurement of structure factors and determination of crystal thickness by electron diffraction (J. Gjønnes and J. W. Steeds)	363
	4.3.8.	Crystal structure determination by high-resolution electron microscopy (J. C. H. Spence and J. M. Cowley)	365
		4.3.8.1. Introduction	365
		4.8.8.2. Lattice-fringe images	366
		4.3.8.3. Crystal structure images 4.3.8.4 Parameters affecting HREM images	308
		4.3.8.5. Computing methods	371
		4.3.8.6. Resolution and hyper-resolution	372
		4.3.8.7. Non-standard methods	372
4.4.	Neut	ron Techniques	374
	4.4.1.	Production of neutrons (G. Lander)	374
	4.4.2.	Devices for neutron beam definition (A. K. Freund and G. Dolling)	375
		4.4.2.1. Collimators, guides, and mirrors	375
		4.4.2.2. Monochromators	3/0
		4.4.2.3. Filters 4.4.2.4. Polarization control devices	381
		Table 4.4.2.1. Some important properties of materials used for neutron monochromator crystals	377
		Table 4.4.2.2. The total scattering cross section σ_s and the resonance energy of a number of elements and isotopes in common use as neutron filters	379
	4.4.3.	Resolution functions (R. Pynn and J. M. Rowe)	382
	4.4.4.	Scattering lengths for neutrons (V. F. Sears)	383
		Table 4.4.4.1. Bound scattering lengths, b, in fm and cross sections, σ , in barns (1 barn = 100 fm ²) of the	
		elements and their isotopes	384
	4.4.5.	Magnetic form factors (P. J. Brown)	391
		Table 4.4.5.1. $\langle j_0 \rangle$ form factors for 3d transition elements and their ions	392
		Table 4.4.5.2. (j_0) form factors for 4a atoms and their ions Table 4.4.5.2. (j_0) form factors for rare-earth ions	393
		Table 4.4.5.4. (i_0) form factors for actinide ions	393
		Table 4.4.5.5. $\langle j_2 \rangle$ form factors for 3d transition elements and their ions	394
		Table 4.4.5.6. $\langle j_2 \rangle$ form factors for 4d atoms and their ions	395
		Table 4.4.5.7. $\langle j_2 \rangle$ form factors for rare-earth ions Table 4.4.5.8. $\langle j_1 \rangle$ form factors for actinide ions	395
		Table 4.4.5.9. (j_2) form factors for 3d atoms and their ions	396
		Table 4.4.5.10. $\langle j_4 \rangle$ form factors for 4d atoms and their ions	397
		Table 4.4.5.11. $\langle j_4 \rangle$ form factors for rare-earth ions	397
		Table 4.4.5.12. $\langle j_4 \rangle$ form factors for actinide ions	398 200
		Table 4.4.5.13. (j_6) form factors for rare-earth ions Table 4.4.5.14. (j_1) form factors for activide ions	399
		$\frac{1}{1} = \frac{1}{1} = \frac{1}$	399
	4.4.0.	Absorption coefficients for neutrons (D. 1. 101. with s) Table 4.4.6.1 Absorption of the elements for neutrons ($\lambda = 1.80$ Å)	399
	D - f	1 auto 4.4.0.1. Ausorption of the elements for heations (n = 1.00 m)	400

References

PART 5: DETERMINATION OF LATTICE PARAMETERS	419
5.1. Introduction (A. J. C. Wilson)	420
5.2. X-RAY DIFFRACTION METHODS: POLYCRYSTALLINE (W. Parrish and A. J. C. Wilson)	421
5.2.1. Introduction	421
5.2.1.1. The techniques available 5.2.1.2. Errors and aberrations: general discussion 5.2.1.3. Errors of the Bragg angle 5.2.1.4. Bragg angle: operational definitions	421 421 421 421
Table 5.2.1.1. Functions of the cell angles in equation (5.2.1.3) for the possible unit cells	421
5.2.2. Wavelength and related problems	422
 5.2.2.1. Errors and uncertainties in wavelength 5.2.2.2. Refraction 5.2.2.3. Statistical fluctuations 	422 422 422
5.2.3. Geometrical and physical aberrations	423
5.2.3.1. Aberrations 5.2.3.2. Extrapolation, graphical and analytical	423 423
5.2.4. Angle-dispersive diffractometer methods: conventional sources	424
Table 5.2.4.1. Centroid displacement $\langle \Delta \theta / \theta \rangle$ and variance W of certain aberrations of an angle-dispersive diffractometer	424
5.2.5. Angle-dispersive diffractometer methods: synchrotron sources	425
5.2.6. Whole-pattern methods	426
5.2.7. Energy-dispersive techniques	426
Table 5.2.7.1. Centroid displacement $\langle \Delta E/E \rangle$ and variance W of certain aberrations of an energy-dispersive diffractometer.	427
5.2.8. Camera methods	427
Table 5.2.8.1. Some geometrical aberrations in the Debye-Scherrer method	428
5.2.9. Testing for remanent systematic error	427
5.2.10. Powder-diffraction standards	428
Table 5.2.10.1.NIST values for silicon standardsTable 5.2.10.2.Reflection angles for tungsten, silver, and siliconTable 5.2.10.3.Silicon standard reflection anglesTable 5.2.10.4.Silicon standard high reflection anglesTable 5.2.10.5.Tungsten reflection anglesTable 5.2.10.6.Fluorophlogopite standard reflection angles	429 429 430 431 432 433
5.2.11. Intensity standards	429
Table 5.2.11.1. NIST intensity standards, SRM 674	433
5.2.12. Factors determining accuracy	431
5.3. X-RAY DIFFRACTION METHODS: SINGLE CRYSTAL (E. Gałdecka)	434
5.3.1. Introduction	434
5.3.1.1. General remarks 5.3.1.2. Introduction to single-crystal methods.	434 435
5.3.2. Photographic methods	437
5.3.2.1. Introduction 5.3.2.2. Moving-crystal methods	437 437
 5.3.2.2.1. Rotating-crystal method 5.3.2.2.2. Moving-film methods 5.3.2.2.3. Combined methods 5.3.2.2.4. Accurate and precise lattice-parameter determinations 5.3.2.2.5. Photographic cameras for investigation of small lattice-parameter changes 	437 437 437 438 438

		5.3.2.3.	The Kossel method and divergent-beam techniques	439
			 5.3.2.3.1. The principle 5.3.2.3.2. Review of methods of accurate lattice-parameter determination 5.3.2.3.3. Accuracy and precision 5.3.2.3.4. Applications 	439 441 443 443
	5.3.3.	Method	s with counter recording	444
		5.3.3.1. 5.3.3.2.	Introduction Standard diffractometers	444 444
			5.3.3.2.1. Four-circle diffractometer 5.3.3.2.2. Two-circle diffractometer	444 445
		5.3.3.3.	Data processing and optimization of the experiment	446
			5.3.3.3.1. Location of the diffraction profile 5.3.3.3.2. Precision of location of the diffraction profile; optimization of the experiment	446 446
		5.3.3.4.	One-crystal spectrometers	448
			 5.3.3.4.1. General characteristics 5.3.3.4.2. Development of methods based on an asymmetric arrangement and their applications 5.3.3.4.3. The Bond method 	448 448 449
			 5.3.3.4.3.1. Description of the method 5.3.3.4.3.2. Systematic errors 5.3.3.4.3.3. Development of the Bond method and its applications 5.3.3.4.3.4. Advantages and disadvantages of the Bond method 	449 450 451 452
		5.3.3.5. 5.3.3.6. 5.3.3.7.	Limitations of traditional methods Multiple-diffraction methods Multiple-crystal – pseudo-non-dispersive techniques	453 453 455
			 5.3.3.7.1. Double-crystal spectrometers 5.3.3.7.2. Triple-crystal spectrometers 5.3.3.7.3. Multiple-beam methods 5.3.3.7.4. Combined methods 	455 457 457 458
		5.3.3.8.	Optical and X-ray interferometry – a non-dispersive technique	459
	5.3.4.	Final re	emarks	459
5.4.	ELEC	rron-D	IFFRACTION METHODS	462
	5.4.1.	Determ	ination of cell parameters from single-crystal patterns (A. W. S. Johnson)	462
		5.4.1.1. 5.4.1.2. 5.4.1.3.	Introduction Zero-zone analysis Non-zero-zone analysis	462 463 463
		Table :	5.4.1.1. Unit-cell information available for photographic recording	462
	5.4.2.	Kikuch	i and HOLZ techniques (A. Olsen)	463
5.5.	NEUT Refer	ron Mi ences	етнодs (B. T. M. Willis)	466 466
PA	RT 6	: INT	ERPRETATION OF DIFFRACTED INTENSITIES	475
6.1.	INTE	NSITY OF	DIFFRACTED INTENSITIES	476
	6.1.1	X-ray s	cattering (E. N. Maslen, A. G. Fox, and M. A. O'Keefe)	476
		6.1.1.1 6.1.1.2 6.1.1.3	Coherent (Rayleigh) scattering Incoherent (Compton) scattering Atomic scattering factor	476 476 476
			6.1.1.3.1. Scattering factor interpolation	487
		6.1.1.4 6.1.1.5 6.1.1.6	. Generalized scattering factors . The temperature factor . The generalized temperature factor	487 505 506
			6.1.1.6.1. Gram-Charlier series 6.1.1.6.2. Fourier-invariant expansions	507 507

		6.1.1.6.3. Cumulant expansion	509
		6.1.1.6.4. Curvilinear density functions	509
		6.1.1.6.5. Model-based curvilinear density functions	510
		6.1.1.6.6. The quasi-Gaussian approximation for curvilinear motion	511
		6.1.1.7. Structure factor	511
		6.1.1.8. Reflecting power of a crystal	511
		Table 6.1.1.1. Mean atomic scattering factors in electrons for free atoms	477
		Table 6.1.1.2. Spherical bonded hydrogen-atom scattering factors	487
		Table 6.1.1.3. Mean atomic scattering factors in electrons for chemically significant ions	488
		Table 6.1.1.4. Coefficients for analytical approximation to the scattering factors of Tables 6.1.1.1 and 6.1.1.3 Table 6.1.1.5. Coefficients for analytical approximation to the scattering factors of Table 6.1.1.1 for the	500
		range 2.0 $A^{-1} < (\sin \theta)/\lambda < 6.0 A^{-1}$ (equation 6.1.1.16)	503
		Table 6.1.1.6. Angle dependence of multipole functions	504
		Table 6.1.1.7. Indices allowed by the site symmetry for the real form of the spherical harmonics $T_{lmp}(\theta, \varphi)$ To block 1.1.9. Cubic harmonics $K(\theta, \phi)$ for cubic site symmetries	505
		Table 6.1.1.8. Cubic narmonics $\mathbf{x}_{ij}(\theta, \varphi)$ for cubic site symmetries Table 6.1.1.0. $f_{ij}(\theta, S) = \int_{0}^{\infty} r^{n} \exp(-\alpha r) i_{ij}(Sr) dr$	506
		Table 6.1.1.9. $J_{ni}(\alpha, \beta) = J_0$ is exp(- $\alpha r) J_i(\beta r) \alpha r$ Table 6.1.1.10. Indices nmn allowed by the site symmetry for the functions $H_n(z)\Phi_{mn}(\phi)$	508
		Table 6.1.1.11. Indices $n_x n_y n_z$ allowed for the basis functions $H_{n_x}(Ax)H_{n_y}(By)H_{n_z}(Cz)$	509
	6.1.2.	Magnetic scattering of neutrons (P. J. Brown)	512
		6.1.2.1. General formulae for the magnetic cross section	512
		6.1.2.2. Calculation of magnetic structure factors and cross sections	512
		6.1.2.3. The magnetic form factor	513
		6.1.2.4. The scattering cross section for polarized neutrons	513
		6.1.2.5. Rotation of the polarization of the scattered neutrons	514
	6.1.3.	Nuclear scattering of neutrons (B. T. M. Willis)	514
		6.1.3.1. Scattering by a single nucleus	515
		6.1.3.2. Scattering by a single atom	515
		6.1.3.3. Scattering by a single crystal	515
6.2.	TRIGO	NOMETRIC INTENSITY FACTORS (H. Lipson)	517
	6.2.1.	Expressions for intensity of diffraction	517
		Table 6.2.1.1. Summary of formulae for integrated intensities of reflection	518
	6.2.2.	The polarization factor	517
	6.2.3.	The angular-velocity factor	517
	6.2.4.	The Lorentz factor	517
	6.2.5.	Special factors in the powder method	517
	6.2.6.	Other factors	517
()	V	Anconnerous (E. N. Maclon)	520
0.3.	X-RAY	Y ABSORPTION (E. N. Masien)	520
	0.3.1.	Linear absorption coefficient	520
		6.3.1.1. True or photoelectric absorption	520 520
		6.3.1.2. Scattering	520
		6.3.1.3. Extinction 6.3.1.4 Attenuation (mass absorption) coefficients	521
	637	Dispersion	521
	633	Absorption corrections	521
	0.5.5.	6221 Spacial cases	522
		6332 Cylinders and spheres	522
		6.3.3.3. Analytical method for crystals with regular faces	525
		6.3.3.4. Gaussian integration	527
		6.3.3.5. Empirical methods	527
		6.3.3.6. Measuring crystals for absorption	529
		Table 6.3.3.1. Transmission coefficients	521
		Table 6.3.3.2. Values of A* for cylinders	523
		Table 6.3.3.3. Values of A* for spheres	523
		Table 6.3.3.4. Values of $(1/A^*)(dA^*/d\mu R)$ for spheres Table 6.3.3.4. Coefficients for interpolation of A^* and \overline{T}	524
		Table 0.3.3.3. Coefficients for interpolation of A' and I	527

U+U+L+	TANK A ANT		

<u>1</u>

64 THE FLOW OF PARAMON IN	$\mathbf{D}_{\mathbf{D}} = \mathbf{D}_{\mathbf{D}} = $	
5.4. THE FLOW OF KADIATION IN	N A REAL CRYSTAL (I. M. Sabine)	530
6.4.1. Introduction		530
6.4.2. The model of a real cr	rystal	530
6.4.3. Radiation flow		530
6.4.4. Evaluation of σ		530
6.4.5. The extinction factor		531
6.4.6. The finite crystal		531
6.4.7. Angular variation of <i>L</i>	8	531
6.4.8. Primary and secondary	y extinction	531
6.4.9. Anisotropy		531
6.4.10. Polarization		532
6.4.11. Asymptotic behaviour	r of the integrated intensity	532
6.4.12. Definitions		532
6.4.13. Application		532
References		533

PART 7: MEASUREMENT OF INTENSITIES

7.1.	DETE	ctors for X-rays	538
	7.1.1.	Photographic film (P. M. de Wolff)	538
	7.1.2.	Geiger counters (W. Parrish)	538
	7.1.3.	Proportional counters (W. Parrish)	539
		 7.1.3.1. The detector system 7.1.3.2. Proportional counters 7.1.3.3. Position-sensitive detectors 7.1.3.4. Resolution, discrimination, efficiency 	539 539 539 539
	7.1.4.	Scintillation and solid-state detectors (W. Parrish)	539
		 7.1.4.1. Scintillation counters 7.1.4.2. Solid-state detectors 7.1.4.3. Energy resolution and pulse-amplitude discrimination 7.1.4.4. Quantum counting efficiency and linearity 7.1.4.5. Escape peaks 	539 540 540 541 542
	7.1.5.	Energy-dispersive detectors (B. Buras and L. Gerward)	542
		 7.1.5.1. Silicon and germanium detectors 7.1.5.2. Alternative detector materials 7.1.5.3. Monochromator scan method for high-momentum resolution 	542 543 543
	7.1.6.	Position-sensitive detectors (U. W. Arndt)	543
		 7.1.6.1. Choice of detector 7.1.6.2. Gas-filled counters 7.1.6.3. Semiconductor detectors 7.1.6.4. Devices with an X-ray-sensitive photocathode 7.1.6.5. Television area detectors with external phosphor 7.1.6.6. Some recent developments 	544 546 549 550 550 550 552
		Table 7.1.6.1. The importance of some detector properties for different X-ray patterns Table 7.1.6.2. X-ray phosphors	544 551
	7.1.7.	X-ray-sensitive TV cameras (J. Chikawa) 7.1.7.1. Signal-to-noise ratio 7.1.7.2. Imaging system 7.1.7.3. Direct method 7.1.7.4. Indirect method 7.1.7.5. Image processing	552 552 553 553 553 554
	7.1.8.	Storage phosphors (Y. Amemiya and J. Chikawa)	554

7.2.	DETECTORS FOR ELECTRONS (J. N. Chapman)		
	7.2.1. Introduction	556	
	7.2.2. Characterization of detectors	556	
	7.2.3. Parallel detectors	557	
	 7.2.3.1. Fluorescent screens 7.2.3.2. Photographic emulsions 7.2.3.3. Detector systems based on an electron-tube device 7.2.3.4. Electronic detection systems based on solid-state devices 7.2.3.5. Imaging plates 	557 557 558 558 558	
	7.2.4. Serial detectors	558	
7.3.	7.2.4.1. Faraday cage7.2.4.2. Scintillation detectors7.2.4.3. Semiconductors detectors	558 559 559	
	7.2.5. Conclusions	559	
	. THERMAL NEUTRON DETECTION (P. Convert and P. Chieux)	561	

7.3.1 Detection processes

	/.3.1.	Detection processes	501
		7.3.1.1. Neutron capture7.3.1.2. Various neutron-detection processes	561 561
		7.3.1.2.1. Detection via gas ionization7.3.1.2.2. Detection via scintillation7.3.1.2.3. Films	561 563 564
		7.3.1.3. Electronic aspects of the detection	565
		7.3.1.3.1. The electronic chain7.3.1.3.2. Controls and adjustments of the electronics7.3.1.3.3. Characteristics of the detectors	565 565 566
		Table 7.3.1.1. Neutron capture reactions used in neutron detectionTable 7.3.1.2. Commonly used detection processesTable 7.3.1.3. A few examples of gas detector characteristics	561 562 564
	7.3.2.	Typical detection systems	567
		7.3.2.1. Single detectors7.3.2.2. Position-sensitive detectors7.3.2.3. Detector assemblies	567 567 568
		Table 7.3.2.1. Characteristics of some PSD's	568
	7.3.3.	Corrections to the intensity measurements depending on the detection system	569
		 7.3.3.1. Single detector 7.3.3.2. Pluri-detector 7.3.3.3. Position-sensitive detectors 	569 569 569
	7.3.4.	Conclusion	569
7.4.	Corr	ection of Systematic Errors	570
	7.4.1.	Absorption	570
	7.4.2.	Thermal diffuse scattering (B. T. M. Willis)	570
		7.4.2.1. TDS correction factor for X-rays (single crystals)7.4.2.2. TDS correction factor for thermal neutrons (single crystals)7.4.2.3. Correction factor for powders	571 573 573
	7.4.3.	Compton scattering (N. G. Alexandropoulos and M. J. Cooper)	574
		 7.4.3.1. Introduction 7.4.3.2. Non-relativistic calculations of the incoherent scattering cross section 7.4.3.3. Relativistic treatment of incoherent scattering 	574 574 576
		Table 7.4.3.1. The energy transfer in the Compton scattering process for selected X-ray energies Table 7.4.3.2. The incoherent scattering function for elements up to $Z = 55$ Table 7.4.3.3. Compton scattering of Mo K α X-radiation through 170° from 2s electrons	574 575 576

	7.4.4.	White radiation and other sources of background (P. Suortti)	578
		7.4.4.1. Introduction	578
		7.4.4.2. Incident beam and sample	578
		7.4.4.3. Detecting system 7.4.4.4 Powder diffraction	580
	_		201
7.5.	STATI	STICAL FLUCTUATIONS (A. J. C. Wilson)	583
	7.5.1.	Counting modes	583
	7.5.2.	rixed-time counting	583
	7.5.3.	Fixed-count timing	583
	7.5.4.	Complicating phenomena	583
	Refer	ences	584
PA	RT 8:	REFINEMENT OF STRUCTURAL PARAMETERS	593
8.1.	LEAST	SQUARES (E. Prince and P. T. Boggs)	594
	8.1.1.	Definitions	594
		8.1.1.1. Linear algebra	594
		8.1.1.2. Statistics	595
	8.1.2.	Principles of least squares	596
	8.1.3.	Implementation of linear least squares	597
		8.1.3.1. Use of the QR factorization	597 507
		8.1.3.2. The horman equations 8.1.3.3. Conditioning	598
	8.1.4.	Methods for nonlinear least squares	598
	52 2	8.1.4.1. The Gauss-Newton algorithm	598
		8.1.4.2. Trust-region methods - the Levenberg-Marquardt algorithm	599
		8.1.4.3. Quasi-Newton, or secant, methods 8.1.4.4. Stopping rules	599 600
		8.1.4.5. Recommendations	601
	8.1.5.	Numerical methods for large-scale problems	601
		8.1.5.1. Methods for sparse matrices	601
		8.1.5.2. Conjugate-gradient methods	602
	8.1.6.	Software for least-squares calculations	603
8.2.	Отне	R REFINEMENT METHODS (E. Prince and D. M. Collins)	605
	8.2.1.	Maximum-likelihood methods	605
	8.2.2.	Robust/resistant methods	605
	8.2.3.	Entropy maximization	607
		8.2.3.1. Introduction	607
		8.2.3.2. Some examples	007
8.3.	Cons	TRAINTS AND RESTRAINTS IN REFINMENT (E. Prince, L. W. Finger, and J. H. Konnert)	609
	8.3.1.	Constrained models	609
		8.3.1.1. Lagrange undetermined multipliers 8.3.1.2. Direct application of constraints	609 609
		Table 8.3.1.1. Symmetry conditions for second cumulant tensors	611
	8.3.2.	Stereochemically restrained least-squares refinement	614
		8.3.2.1. Stereochemical constraints as observational equations	614
		Table 8.3.2.1. Coordinates of atoms in standard groups appearing in polypeptides and proteins Table 8.3.2.2. Ideal values for distances, torsion angles, etc. for a glycine-alanine dipeptide with a trans	615
		peptide bond Table 8.3.2.3 Typical values of standard deviations for use in determining weights in restrained refinement	616
		of protein structures	617

8.4.	STATIS	stical Signifi	CANCE TESTS (E. Prince and C. H. Spiegelman)	618
	8.4.1.	The χ^2 distribution	ition	618
		Table 8.4.1.1.	Values of χ^2/ν for which the c.d.f. $\Psi(\chi^2, \nu)$ has the values given in the column headings, for various values of ν	619
	8.4.2.	The F distribu	tion	619
		Table 8.4.2.1.	Values of the F ratio for which the c.d.f. $\Psi(F, \nu_1, \nu_2)$ has the value 0.95, for various choices of ν_1 and ν_2	620
	8.4.3.	Comparison of	different models	620
		Table 8.4.3.1.	Values of t for which the c.d.f. $\Psi(t, v)$ has the values given in the column headings, for various values of v	620
	8.4.4.	Influence of in	dividual data points	621
8.5.	Detec	ction and Tri	EATMENT OF SYSTEMATIC ERROR (E. Prince and C. H. Spiegelman)	622
	8.5.1.	Accuracy		622
	8.5.2.	Lack of fit		622
	8.5.3.	Influential data	a points	623

623

8.5.4. Plausibility of results

8.6.	6. THE RIETVELD METHOD (B. T. M. Willis and A. Albinati)			625
	8.6.1.	Basic th	leory	625
		8.6.1.1. 8.6.1.2.	Neutrons: fixed wavelength Other diffraction geometries	625 626
	8.6.2.	Problem	ns with the Rietveld method	626
		8.6.2.1. 8.6.2.2. 8.6.2.3. 8.6.2.4. 8.6.2.5.	Indexing Peak-shape function (PSF) Background Preferred orientation Statistical validity	626 626 626 626
8.7.	Anal	YSIS OF (CHARGE AND SPIN DENSITIES (P. Coppens and P. J. Becker)	627
	8.7.1.	Outline	of this chapter	627
	8.7.2 .	Electron	n densities and the <i>n</i> -particle wavefunction	627
	8.7.3. Charge densities		densities	627
		8.7.3.1. 8.7.3.2. 8.7.3.3.	Introduction Modelling of the charge density Physical constraints	627 628 629
			 8.7.3.3.1. Electroneutrality constraint 8.7.3.3.2. Cusp constraint 8.7.3.3.3. Radial constraint 8.7.3.3.4. Hellmann-Feynman constraint 	629 629 629 629
		8.7.3.4.	Electrostatic moments and the potential due to a charge distribution	629
			8.7.3.4.1. Moments of a charge distribution	629
8.7.3.4.1.1. Moments as a function of the atomic multipole expansion 8.7.3.4.1.2. The effect of origin shift on the outer moments 8.7.3.4.1.3. Electrostatic moments of a subvolume of space by Fourier summation 8.7.3.4.2. The electrostatic potential		8.7.3.4.1.1. Moments as a function of the atomic multipole expansion 8.7.3.4.1.2. The effect of origin shift on the outer moments 8.7.3.4.1.3. Electrostatic moments of a subvolume of space by Fourier summation	630 630 630	
		8.7.3.4.2. The electrostatic potential	631	
			8.7.3.4.2.1. The electrostatic potential and its derivatives 8.7.3.4.2.2. Electrostatic potential outside a charge distribution	631 631
			8.7.3.4.3. Electrostatic functions of crystals by Fourier summation 8.7.3.4.4. The total energy of a crystal as a function of the electron density	632 632
		8.7.3.5. 8.7.3.6.	Quantitative comparison with theory Occupancies of transition-metal valence orbitals from multipole coefficients	633 633

8.7.3.7. Thermal smearing of theoretical densities	634
8.7.3.7.1. General considerations 8.7.3.7.2. Reciprocal-space averaging over external vibrations	634 635
8.7.3.8. Errors in experimental electron densities 8.7.3.9. Errors in derived functions	636 636
Table 8.7.3.1. Definition of difference density functions Table 8.7.3.2. Expressions for the shape factors S for a parallelepiped with edges δ_x , δ_y , and δ_z Table 8.7.3.3. The matrix M^{-1} relating d-orbital occupancies P_{ij} to multipole populations P_{lm} Table 8.7.3.4. Orbital-multipole relations for square-planar complexes (point group D_{4h}) Table 8.7.3.5. Orbital-multiple relations for trigonal complexes	628 631 634 634 634
8.7.4. Spin densities	636
8.7.4.1. Introduction 8.7.4.2. Magnetization densities from neutron magnetic elastic scattering 8.7.4.3. Magnetization densities and spin densities	636 636 637
 8.7.4.3.1. Spin-only density at zero temperature 8.7.4.3.2. Thermally averaged spin-only magnetization density 8.7.4.3.3. Spin density for an assembly of localized systems 8.7.4.3.4. Orbital magnetization density 	637 638 638 638
8.7.4.4. Probing spin densities by neutron elastic scattering	639
 8.7.4.4.1. Introduction 8.7.4.4.2. Unpolarized neutron scattering 8.7.4.4.3. Polarized neutron scattering 8.7.4.4.4. Polarized neutron scattering of centrosymmetric crystals 8.7.4.4.5. Polarized neutron scattering in the noncentrosymmetric case 8.7.4.4.6. Effect of extinction 8.7.4.4.7. Error analysis 	639 639 639 639 639 640 640
8.7.4.5. Modelling the spin density	640
8.7.4.5.1. Atom-centred expansion	640
8.7.4.5.1.1. Spherical atom model 8.7.4.5.1.2. Crystal-field approximation 8.7.4.5.1.3. Scaling of the spin density	640 640 641
8.7.4.5.2. General multipolar expansion 8.7.4.5.3. Other types of models	641 641
8.7.4.6. Orbital contribution to the magnetic scattering	641
8.7.4.6.1. The dipolar approximation 8.7.4.6.2. Beyond the dipolar approximation 8.7.4.6.3. Electronic structure of rare-earth elements	642 642 643
8.7.4.7. Properties derivable from spin densities	643
8.7.4.7.1. Vector fields 8.7.4.7.2. Moments of the magnetization density	643 643
8.7.4.8. Comparison between theory and experiment 8.7.4.9. Combined charge and spin density analysis 8.7.4.10. Magnetic X-ray scattering separation between spin and orbital magnetism	643 643 644
8.7.4.10.1. Introduction 8.7.4.10.2. Magnetic X-ray structure factor as a function of photon polarization	644 644
8.8. ACCURATE STRUCTURE-FACTOR DETERMINATION WITH ELECTRON DIFFRACTION (J. Gjønnes)	646
Table 8.8.1. A comparison of measurements of the X-ray structure factor F ^x for copper	648
References	649
PART 9: BASIC STRUCTURAL FEATURES	653
9.1. SPHERE PACKINGS AND PACKINGS OF ELLIPSOIDS (E. Koch and W. Fischer)	654
9.1.1. Sphere packings and packings of circles	654
9.1.1.1. Definitions	654

9.1.1.2. Homogeneous packings of circles 9.1.1.3. Homogeneous sphere packings 9.1.1.4. Applications	654 655 657
9.1.1.5. Interpenetrating sphere packings	658
Table 9.1.1.1. Types of circle packings in the plane Table 9.1.1.2. Examples for sphere packings with high contact numbers and high densities and with l contact numbers and low densities	654 ow 655
	658
9.1.2. Packings of ellipses and ellipsolds	0.30
2. LAYER STACKING	660
9.2.1. Layer stacking in close-packed structures (D. Pandey and P. Krishna)	660
9.2.1.1. Close packing of equal spheres	660
9.2.1.1.1. Close-packed layer9.2.1.1.2. Close-packed structures9.2.1.1.3. Notations for close-packed structures	660 660 660
9.2.1.2. Structure of compounds based on close-packed layer stackings	661
 9.2.1.2.1. Voids in close packing 9.2.1.2.2. Structures of SiC and ZnS 9.2.1.2.3. Structure of CdI₂ 9.2.1.2.4. Structure of GaSe 	661 661 662 662
 9.2.1.3. Symmetry of close-packed layer stackings of equal spheres 9.2.1.4. Possible lattice types 9.2.1.5. Possible space groups 9.2.1.6. Crystallographic uses of Zhdanov symbols 9.2.1.7. Structure determination of close-packed layer stackings 	663 664 664 664
 9.2.1.7.1. General considerations 9.2.1.7.2. Determination of the lattice type 9.2.1.7.3. Determination of the identity period 9.2.1.7.4. Determination of the stacking sequence of layers 	664 664 665 665
9.2.1.8. Stacking faults in close-packed structures	665
9.2.1.8.1. Structure determination of one-dimensionally disordered crystals	666
Table 9.2.1.1. Common close-packed metallic structures Table 9.2.1.2. List of SiC polytypes with known structures in order of increasing periodicity Table 9.2.1.3. Intrinsic-fault configurations in the $6H(A_0B_1C_2A_3C_4B_5, \cdots)$ structure Table 9.2.1.4. Intrinsic-fault configurations in the 9R $(A_0B_1A_2C_0A_1C_2B_0C_1B_2, \cdots)$ structure	661 662 666 667
9.2.2. Layer stacking in general polytypic structures (S. Ďurovič)	667
9.2.2.1. The notion of polytypism 9.2.2.2. Symmetry aspects of polytypism	667 668
 9.2.2.2.1. Close packing of spheres 9.2.2.2.2. Polytype families and OD groupoid families 9.2.2.2.3. MDO polytypes 9.2.2.2.4. Some geometrical properties of OD structures 9.2.2.2.5. Diffraction pattern - structure analysis 9.2.2.2.6. The vicinity condition 9.2.2.2.7. Categories of OD structures 	668 669 669 670 671 671 671
9.2.2.2.7.1. OD structures of equivalent layers 9.2.2.2.7.2. OD structures with more than one kind of layer	671 672
9.2.2.2.8. Desymmetrization of OD structures 9.2.2.2.9. Concluding remarks	673 673
9.2.2.3. Examples of some polytypic structures	674
9.2.2.3.1. Hydrous phyllosilicates	674
9.2.2.3.1.1. General geometry 9.2.2.3.1.2. Diffraction pattern and identification of individual polytypes	674 676
9.2.2.3.2. Stibivanite Sb_2VO_5 9.2.2.3.3. γ -Hg_3S_2Cl_2 9.2.2.3.4. Remarks for authors	678 679 680

	9.2.2.4. List of some polytypic structures	680
9.3.	TYPICAL INTERATOMIC DISTANCES: METALS (L. D. Calvert)	681
	Table 9.3.1. Metallic radii for atoms with $CN = 12$ Table 9.3.2. Data used for predicting structure and compound formation	681 682
9.4.	TYPICAL INTERATOMIC DISTANCES: INORGANIC COMPOUNDS (G. Bergerhoff and K. Brandenburg)	683
	Table 9.4.2.1. Typical interatomic distances in inorganic structures	684
9.5.	TYPICAL INTERATOMIC DISTANCES: ORGANIC COMPOUNDS (F. H. Allen, O. Kennard, D. G. Watson, L. Brammer, A. G. Orpen, and R. Taylor)	685
	9.5.1. Introduction	685
	9.5.2. Methodology	685
	9.5.3. Content and arrangement of the table	687
	9.5.4. Discussion	689
	Table 9.5.1.1. Average lengths for bonds involving the elements H, B, C, N, O, F, Si, P, S, Cl, As, Se, Br, Te and I	691

9.6.	TYPICAL INTERATOMIC DISTANCES: ORGANOMETALLIC COMPOUNDS AND COORDINATION COMPLEXES OF THE d- and f-Block Metals (A. G. Orpen, L. Brammer, F. H. Allen, O. Kennard, D. G. Watson, and R. Taylor)	707
	9.6.1. Introduction	707
	9.6.2. Methodology	707
	9.6.3. Content and arrangement of table of interatomic distances	709
	9.6.4. Discussion	713
	Table 9.6.3.1. Ligand index	709
	Table 9.6.3.2. Numbers of entries in Table 9.6.3.3 Table 9.6.3.3. Interatomic distances	712 713
9.7.	THE SPACE-GROUP DISTRIBUTION OF MOLECULAR ORGANIC STRUCTURES (A. J. C. Wilson)	792
	Table 9.7.1. Observed and calculated frequencies of space-group types among molecular organic compounds in the monoclinic system	793
	Table 9.7.2. Observed and calculated frequencies of space-group types among molecular organic compounds in the orthorhombic system (geometric crystal class 222)	793
	Table 9.7.3. Observed and calculated frequencies of space-group types among molecular organic compounds in the orthorhombic system (geometric crystal class mm)	794
	Table 9.7.4. Observed and calculated frequencies of space-group types among molecular organic compounds in the orthorhombic system (geometric crystal class mmm)	794
	Table 9.7.5. Observed frequency of occurrence of space-group types in the tetragonal, trigonal, hexagonal, and cubic	705
	systems Table 9.7.6, An example from the more symmetric crystal systems	795 796
9.8.	INCOMMENSURATE AND COMMENSURATE MODULATED STRUCTURES (T. Janssen, A. Janner, A. Looijenga-Vos, and P. M. de Wolff)	797
	9.8.1. Introduction	797
	9.8.1.1. Modulated crystal structures 9.8.1.2. The basic ideas of higher-dimensional crystallography 9.8.1.3. The simple case of a displacively modulated crystal	797 798 799
	9.8.1.3.1. The diffraction pattern 9.8.1.3.2. The symmetry	799 799
	9.8.1.4. Basic symmetry considerations	800
	 9.8.1.4.1. Bravais classes of vector modules 9.8.1.4.2. Description in four dimensions 9.8.1.4.3. Four-dimensional crystallography 9.8.1.4.4. Generalized nomenclature 9.8.1.4.5. Four-dimensional space groups 	800 801 801 802 802
	9.8.1.5. Occupation modulation	803
	9.8.2. Outline for a superspace-group determination	803

9.8.3.	Introduction to the tables	805
	9.8.3.1. Tables of Bravais lattices9.8.3.2. Tables of geometric and arithmetic crystal classes9.8.3.3. Tables of superspace groups	805 806 806
	9.8.3.3.1. Symmetry elements 9.8.3.3.2. Reflection conditions	806 811
	9.8.3.4. Guide to the use of the tables9.8.3.5. Examples9.8.3.6. Ambiguities in the notation	824 826 826
	Table 9.8.3.1.(a). (2+1)-Dimensional Bravais classes for incommensurate structures Table 9.8.3.1(b). (2+2)-Dimensional Bravais classes for incommensurate structures Table 9.8.3.2(a). (3+1)-Dimensional Bravais classes for incommensurate structures Table 9.8.3.2(b). (3+1)-Dimensional Bravais classes for commensurate structures Table 9.8.3.3. (3+1)-Dimensional point groups and arithmetic crystal classes Table 9.8.3.4(a). (2+1)-Dimensional superspace groups Table 9.8.3.4(b). (2+2)-Dimensional superspace groups Table 9.8.3.5. (3+1)-Dimensional superspace groups Table 9.8.3.6. Centring reflection conditions for (3+1)-dimensional Bravais classes	805 806 807 808 809 810 811 812 825
9.8.4.	Theoretical foundation	827
	9.8.4.1. Lattices and metric 9.8.4.2. Point groups	827 828
	9.8.4.2.1. Laue class 9.8.4.2.2. Geometric and arithmetic crystal classes	828 829
	9.8.4.3. Systems and Bravais classes	829
	9.8.4.3.1. Holohedry9.8.4.3.2. Crystallographic systems9.8.4.3.3. Bravais classes	829 829 830
	9.8.4.4. Superspace groups	830
	9.8.4.4.1. Symmetry elements 9.8.4.4.2. Equivalent positions and modulation relations 9.8.4.4.3. Structure factor	830 830 831
9.8.5.	Generalizations	831
	9.8.5.1. Incommensurate composite crystal structures 9.8.5.2. The incommensurate versus the commensurate case	831 832
Refer	ences	836

PART 10: PRECAUTIONS AGAINST RADIATION INJURY (D. C. Creagh and S. Martinez-Carrera)

10.1.	INTRODUCTION	846
	10.1.1. Definitions	846
	10.1.2. Objectives of radiation protection	847
	10.1.3. Responsibilities	847
	 10.1.3.1. General 10.1.3.2. The radiation safety officer 10.1.3.3. The worker 10.1.3.4. Primary dose limits 	847 847 848 848
	Table 10.1.1. The relationship between SI and the earlier system of units Table 10.1.2. Maximum primary dose limit per quarter Table 10.1.3. Quality factors (QF)	846 848 848
10.2.	Protection from Ionizing Radiation	849
	10.2.1. General	849
	10.2.2. Sealed sources and radiation-producing apparatus	849
	10.2.2.1. Enclosed installations	849

10.2.2.2. Open installations	849
10.2.2.3. Sealed sources	849
10.2.2.4. X-ray diffraction and X-ray analysis apparatus	849
10.2.2.5. Particle accelerators	849
10.2.3. Ionizing-radiation protection – unsealed radioactive materials	850
10.3. Responsible Bodies	851
Table 10.3.1. Regulatory authorities	851
References	853
Author Index	855
Subject Index	

xxvii

10

×